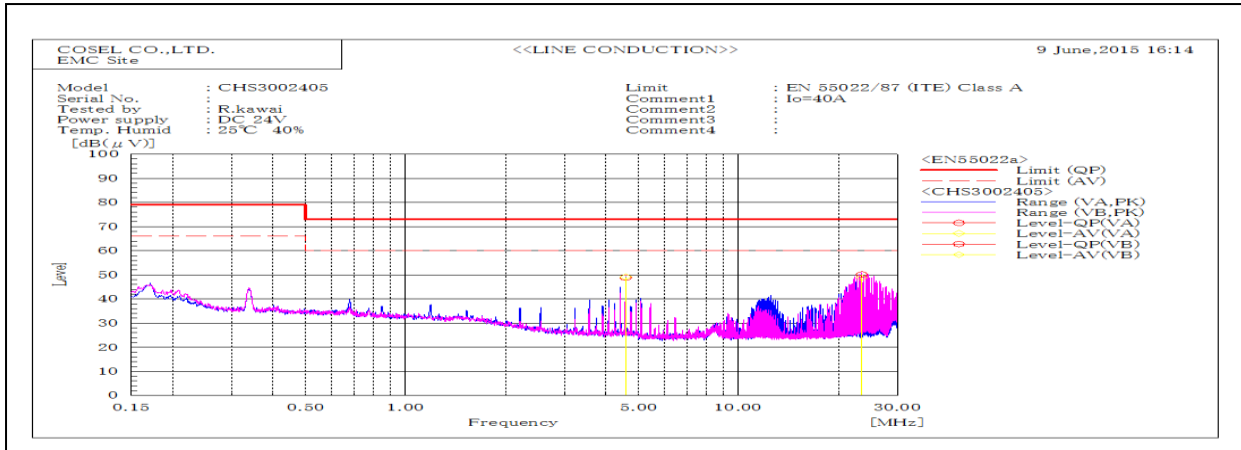
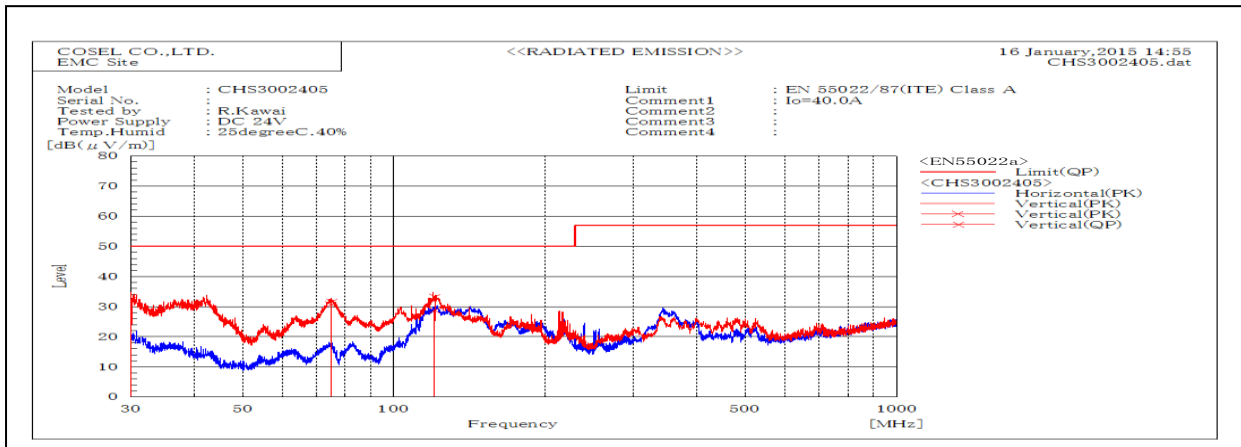


DATA SHEET		Date	10-Jun-15
Model	CHS3002405	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Kawai



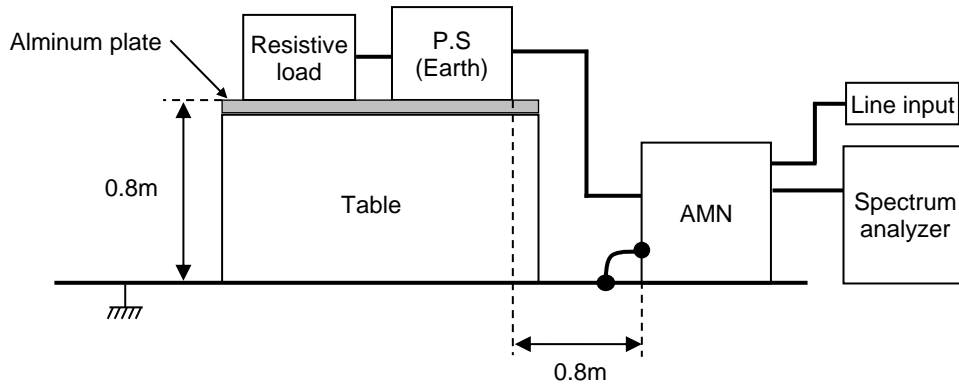
Frequency MHz	Ham	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
4.58812		VA	28.5	28.9	20.3	48.8	49.2	73	60	24.2	10.8	Pass	
23.4577		VB	29.2	27.9	20.9	50.1	48.8	73	60	22.9	11.2	Pass	



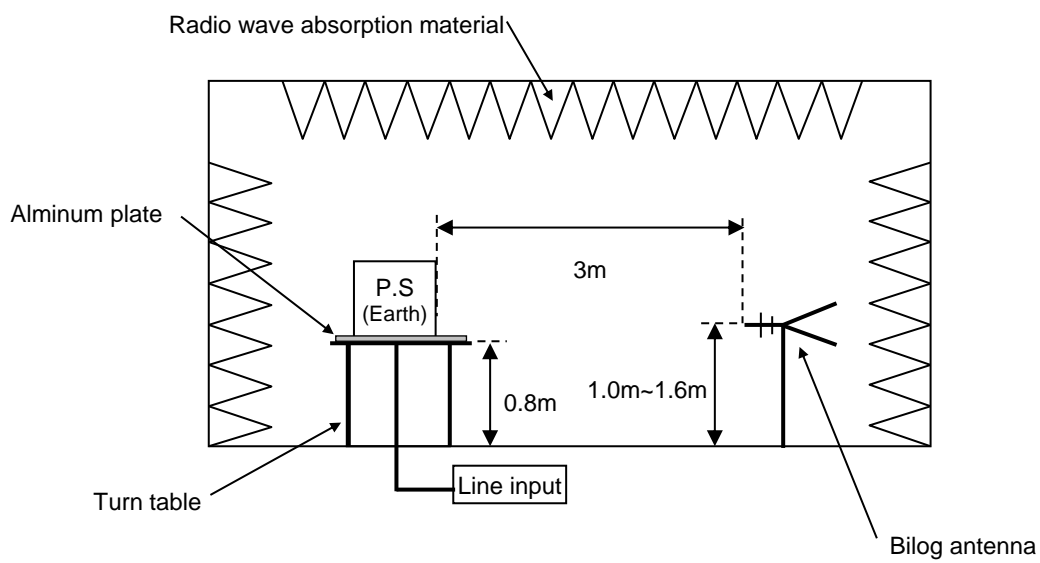
Frequency MHz	Polarization	Stability	Reading dB(uV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP		QP	QP					
30.002	V	Stable	45.8	-13.5	32.3	50	17.7	Pass	116	110	
75.053	V	Stable	51	-20.4	30.6	50	19.4	Pass	105	88	
120.475	V	Stable	45.5	-16.9	28.6	50	21.4	Pass	114	104	

DATA SHEET		Date	10-Jun-15
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Kawai

## 1. Line conduction



## 2. Radiated emission



## Conditions

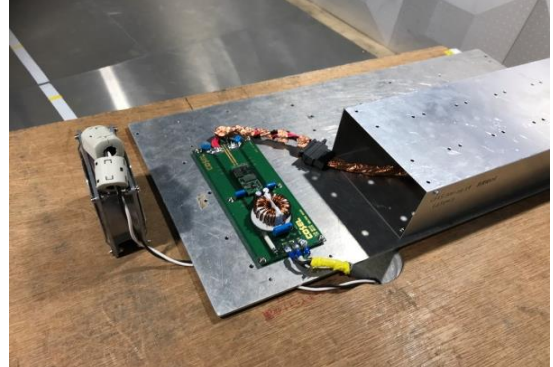
Test : EMI  
 Model Name : CHS30024□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

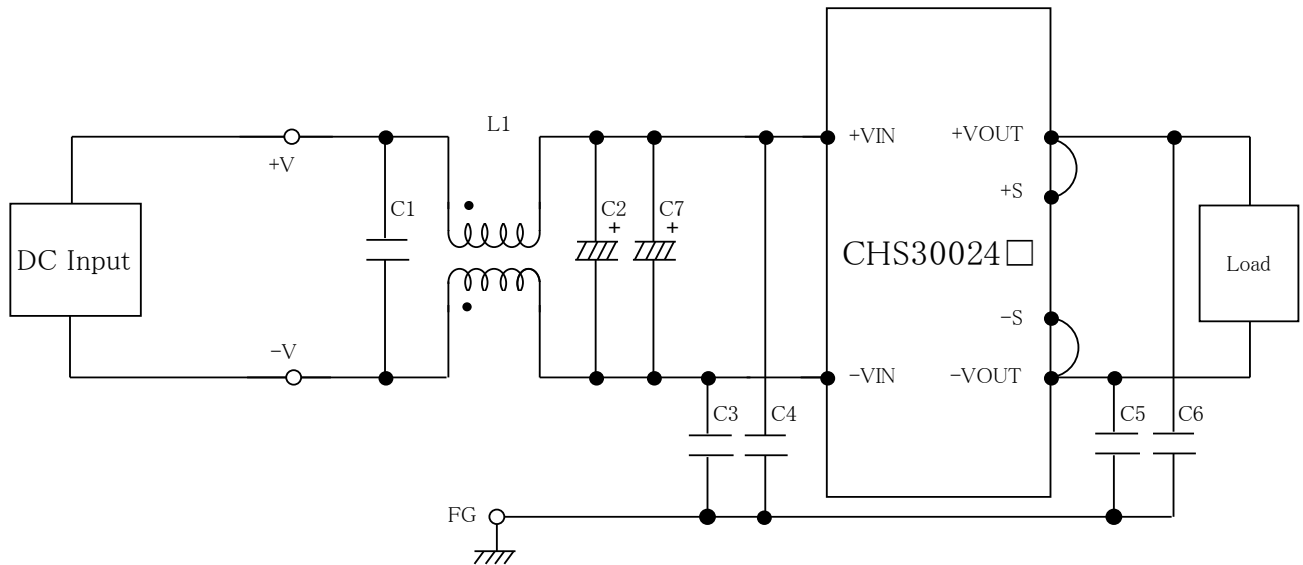


Fig.1 Testing circuitry

- L1 : 1mH SC-20-10JH (TOKIN)
- C1 : 250V 2.2  $\mu$ F FPD22E225J4 (NITSUKO)
- C2,C7 : 50V 330  $\mu$ F PWseries (nichicon)
- C3,C4 : 630V 0.068  $\mu$ F FPD22J683J4(NITSUKO)
- C5,C6 : 630V 0.033  $\mu$ F FPD22J333J4(NITSUKO)